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| Notice of References Cited | Application/Control No. 10/694,218 | Applicant(s)/Patent Under Reexamination HIRANO, SHINTARO | |
| | Examiner Tianjie Chen | Art Unit 2652 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-6,005,831 A | 12-1999 | Park, Dong-Kyun | 369/30.8 |
| | B | US-2004/0081035 A1 | 04-2004 | Fujishima, Yoshikazu | 369/030.36 |
| | C | US-6,810,524 B2 | 10-2004 | Deo, Hisao | 720/606 |
| | D | US-6,091,677 A | 07-2000 | Akiyama et al. | 369/30.93 |
| | E | US-5,742,571 | 04-1998 | Hoshino et al. | 369/30.98 |
| | F | US-5,654,944 | 08-1997 | Lee et al. | 369/30.06 |
| | G | US-5,293,362 A | 03-1994 | Sakurai et al. | 369/30.8 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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